

# High-Voltage, High-Power Silicon N-P-N Power Transistor

For Switching and Linear Applications in Military, Industrial and Commercial Equipment

# RCA410

### Features:

- Maximum safe-area-of-operation curves
- Low saturation voltage:  $V_{CE}^{(sat)} = 0.8V$  max
- High voltage rating:  $V_{CEO}^{(sus)} = 200V$
- High dissipation rating:  $P_T = 125W$
- Steel Hermetic TO-3 Package

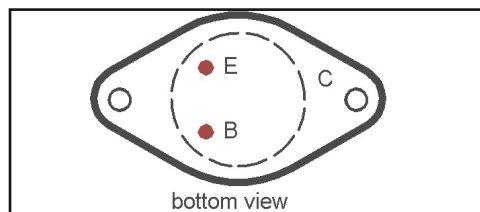
### Applications:

- Inverter
- Deflection Circuits
- Switching Regulators
- High-Voltage Bridge Amplifiers
- Ignition circuits

The RCA410 is an epitaxial silicon n-p-n power transistor utilizing a multiple-emitter-site structure. This device employs the popular TO-3 package.

Featuring high-breakdown voltage ratings and low saturation voltage values, the RCA410 is especially suitable for use in inverters, deflection circuits, switching regulators, high voltage bridge amplifiers, ignition circuits and other high-voltage switching applications.

### Terminal Designations



bottom view

### JEDEC TO-3

### MAXIMUM RATINGS, Absolute-Maximum Values:

$V_{CBO}$	200	V
$V_{CEO}^{(sus)}$	200	V
$V_{EBO}$	5	V
$I_C$	7	A
$I_{CM}$	10	A
$I_B$	2	A
$P_T$ $T_C \leq 25^\circ C$ , $V_{CE}$ up to 75V	125	W
$P_T$ $T_C > 25^\circ C$ , $V_{CE}$ above 75V	see Fig. 1	W/°C
$T_{stg}$ $T_J$	-65 to +200	°C
$T_L$ At distance $\geq 1/32$ in. (0.8mm) from seating plane for 10s max.	230	°C

# RCA410

## Electrical Characteristics, at Case Temperature ( $T_C$ ) = 25°C

Unless Otherwise Specified

Characteristic	Symbol	Test Conditions					Limits			Units
		DC Collector Voltage (V)	DC Emitter or Base Voltage (V)		DC Current (A)		Min.	Typ.	Max.	
		$V_{CE}$	$V_{EB}$	$V_{BE}$	$I_C$	$I_B$				
Collector Cutoff Current with base open	$I_{CEO}$	200					-	-	0.25	mA
with base-emitter junction reverse biased & $T_C$ 125°C	$I_{CEV}$	200		-1.5			-	-	0.5	
Emitter Cutoff Current	$I_{EBO}$		5				-	-	5.0	mA
DC Forward Current Transfer Ratio	$h_{FE}$	5			1.0 <sup>a</sup>		30	-	90	
		5			2.5 <sup>a</sup>		10	-	-	
Collector to Emitter Sustaining Voltage with base open	$V_{CEO}^{(sus)b}$				0.1		200 <sup>b</sup>	-	-	V
Base to Emitter Saturation Voltage	$V_{BE}^{(sat)}$				1.0 <sup>a</sup>	0.1	-	0.9	1.5	V
Collector to Emitter Saturation Voltage	$V_{CE}^{(sat)}$				1.0 <sup>a</sup>	0.1	-	0.2	0.8	V
Second Breakdown Collector Current (With base forward biased) Pulse duration (non-repetitive) 1s	$I_{S/b}^c$	150					0.3	-	-	A
Gain Bandwidth Product	$f_T$	10			0.2		-	4	-	MHz
Switching Time Rise	$f_r$				1.0	0.1 ( $I_{B1}$ )	-	0.35	-	
						-0.5 ( $I_{B2}$ )				
Storage	$f_s$				1.0	0.1 ( $I_{B1}$ )	-	1.4	-	$\mu s$
						-0.5 ( $I_{B2}$ )				
Fall	$f_f$				1.0	0.1 ( $I_{B1}$ )	-	0.15	-	
						-0.5 ( $I_{B2}$ )				
Thermal Resistance (Junction to Case)	$R_{\theta JC}$	10			5		-	-	1.4	°C/W

**a** Pulsed: pulse duration  $\leq 350\mu s$ , duty factor = 2%

**b CAUTION:** The sustaining voltage  $V_{CEO}^{(sus)}$  *MUST NOT* be measured on a curve tracer

**c**  $I_{S/b}$  is defined as the current at which second breakdown occurs at a specified collector voltage with the emitter-base junction forward-biased for transistor operation in the active region

## Power Dissipation

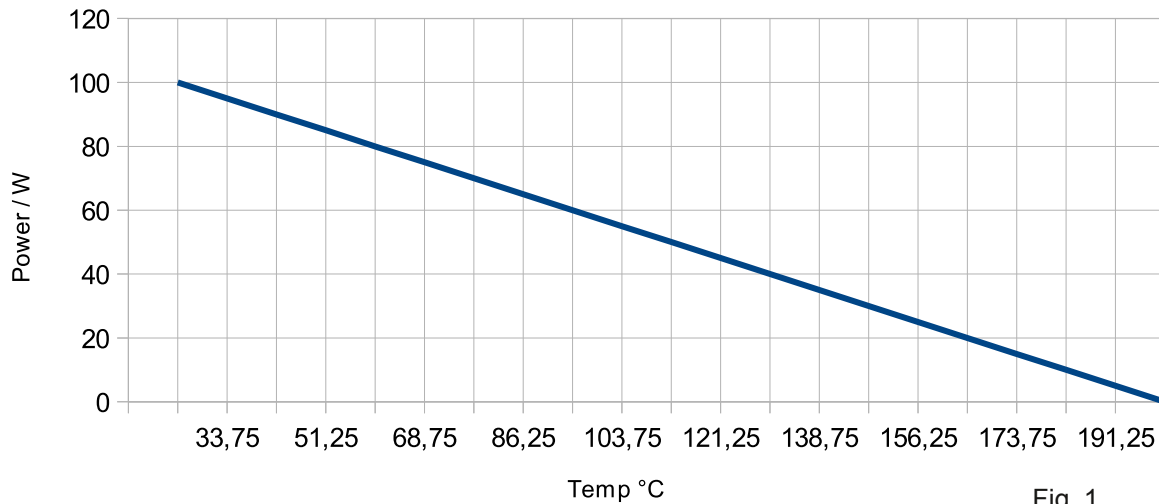


Fig. 1

- $I_C$  - continuous collector current
- $I_{CM}$  - peak collector current
- $I_{CER}$  - collector-cutoff current with specified resistance between base and emitter
- $I_{CEX}$  - collector-cutoff current with specified circuit between base and emitter
- $I_B$  - continuous base current
- $I_{EBO}$  - emitter-cutoff current, collector open
- $I_{S/b}$  - forward-bias, second break-down collector current
- $V_{CBO}$  - collector-to-base voltage, emitter open
- $V_{CEO}$  - collector-to-emitter voltage, base open
- $V_{CEO}^{(sus)}$  - collector-to-emitter sustaining voltage, base open
- $V_{CER}^{(sus)}$  - collector-to-emitter sustaining voltage with specified resistance between base and emitter
- $V_{EBO}$  - emitter-to-base voltage, collector open
- $V_{BE}$  - base-to-emitter voltage
- $V_{CE}^{sat}$  - collector-to-emitter saturation voltage
- $C_{OB}$  - common-base output capacitance
- $C_{OBO}$  - open circuit common-base output capacitance
- $fT$  - gain-bandwidth product (unity-gain frequency for devices in which gain roll-off has a -1 slope)
- $h_{FE}$  - dc forward-current transfer ratio
- $|h_{fe}|$  - magnitude of common-emitter, small-signal, short-circuit, forward-current transfer ratio
- $R_{BE}$  - external base-to-emitter resistance
- $R_{\theta JC}$  - thermal resistance, junction-to-case
- $P_T$  - transistor dissipation at specified temperature
- $t_f$  - fall time
- $t_r$  - rise time
- $t_s$  - storage time
- $T_C$  - case temperature
- $T_{stg}$  - storage temperature
- $T_J$  - operating (junction) temperature
- $T_L$  - lead temperature during soldering
- $\theta$  - conduction angle